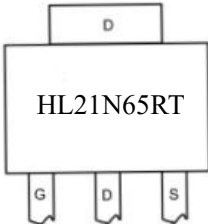
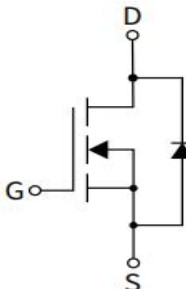


Features ➤ Super Low Gate Charge ➤ 100% EAS Guaranteed ➤ Green Device Available ➤ Excellent CdV/dt effect decline ➤ Advanced trench gate super junction technology	Bvdss	Rdson	ID
	650V	160mΩ	21A
	Application ➤ Power factor correction (PFC) ➤ Switching power supply (SMPS) ➤ LED driver		



Package		
 HL21N65RT Marking and pin assignment	 G D S TO-220 top view	 D G S Schematic diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Quantity
HL21N65RT	HL21N65RT	TO220	50

Absolute Maximum Ratings ($T_C=25^{\circ}\text{C}$ unless otherwise specified)

Parameter		Symbol	Value	Unit
Drain-Source Voltage		V_{DS}	650	V
Gate-Source Voltage		V_{GS}	± 30	V
Continuous Drain Current $V_{GS}@10V^1$	$T_C=25^{\circ}\text{C}$	I_D	21	A
	$T_C=100^{\circ}\text{C}$		13	A
Pulsed Drain Current ²		I_{DM}	62	A
Single Pulsed Avalanche Energy ³		E_{AS}	220	mJ
Avalanche Current		I_{AS}	-	A
Total Power Dissipation ⁴	$T_C = 25^{\circ}\text{C}$	P_D	245	W
Operating Junction Temperature Range		T_J	-55~+150	$^{\circ}\text{C}$
Storage Temperature Range		T_{STG}	-55~+150	$^{\circ}\text{C}$

Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-Ambient ¹	$R_{\theta JA}$	68	$^{\circ}\text{C/W}$
Thermal Resistance Junction-Case ¹	$R_{\theta JC}$	0.51	$^{\circ}\text{C/W}$



Ordering Information

Ordering Number	Package	Pin Assignment			Packing
Halogen Free		G	D	S	
HL21N65RT	TO220	1	2	3	Tube

Electrical Characteristics ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D=250\mu\text{A}$, $V_{GS}=0\text{V}$	650	-	-	V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=650\text{V}$, $V_{GS}=0\text{V}$, $T_J=25^{\circ}\text{C}$	-	-	1	μA
		$V_{DS}=650\text{V}$, $V_{GS}=0\text{V}$, $T_J=100^{\circ}\text{C}$	-	-	100	
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 30\text{V}$, $V_{DS}=0\text{V}$	-	-	± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}$, $I_D=250\mu\text{A}$	3.2	-	4.6	V
Static Drain-Source On-Resistance ²	$R_{DS(on)}$	$V_{GS}=10\text{V}$, $I_D=16\text{A}$	-	160	200	m Ω
Forward Transconductance	g_{fs}	$V_{DS}=20\text{V}$, $I_D=10\text{A}$	-	14.5	-	S
Gate Resistance	R_g	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$	-	1.5	-	Ω
Total Gate Charge	Q_g	$V_{DS}=520\text{V}$, $V_{GS}=10\text{V}$, $I_D=10\text{A}$	-	41	-	nC
Gate Source Charge	Q_{gs}		-	12	-	
Gate Drain Charge	Q_{gd}		-	20	-	
Turn-On Delay Time	$T_{d(on)}$	$V_{GS}=10\text{V}$, $V_{DS}=325\text{V}$, $I_D=20\text{A}$, $R_G=10\Omega$	-	43	-	ns
Rise Time	T_r		-	58	-	
Turn-Off Delay Time	$T_{d(off)}$		-	105	-	
Fall Time	T_f		-	36	-	
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}$, $V_{DS}=100\text{V}$, $f=1\text{MHz}$	-	1459	-	pF
Output Capacitance	C_{oss}		-	62	-	
Reverse Transfer Capacitance	C_{rss}		-	2	-	
Continuous Source Current ^{1,4}	I_S	$V_G=V_D=0\text{V}$, Force Current	-	-	21	A
Diode Forward Voltage ²	V_{SD}	$I_S=16\text{A}$, $V_{GS}=0\text{V}$, $T_J=25^{\circ}\text{C}$	-	-	1.1	V
Reverse Recovery Time	t_{rr}	$IF=10\text{A}$, $di/dt=100\text{A}/\mu\text{s}$, $T_J=25^{\circ}\text{C}$	-	108	-	ns
Reverse Recovery Charge	Q_{rr}		-	0.54	-	nC

Notes:

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $T_J=25^{\circ}\text{C}$, $V_{DD}=200\text{V}$, $V_{GS}=10\text{V}$, $L=50\text{mH}$

4.The power dissipation is limited by 150°C junction temperature

5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Performance Characteristics

Fig 1. Output Characteristics ($T_J=25^\circ\text{C}$)

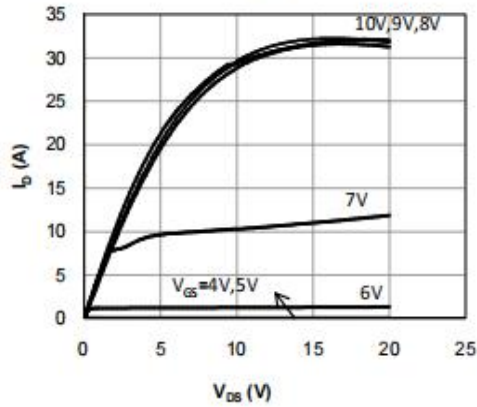


Fig 2. Output Characteristics ($T_J=150^\circ\text{C}$)

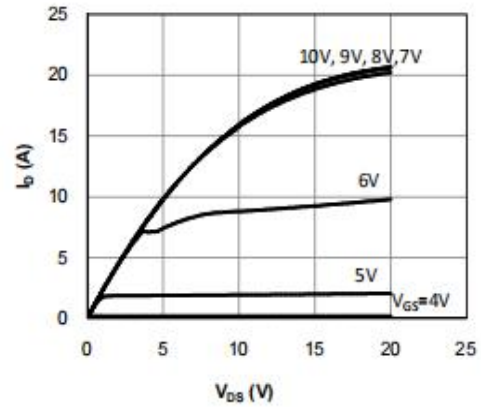


Fig 3: Transfer Characteristics

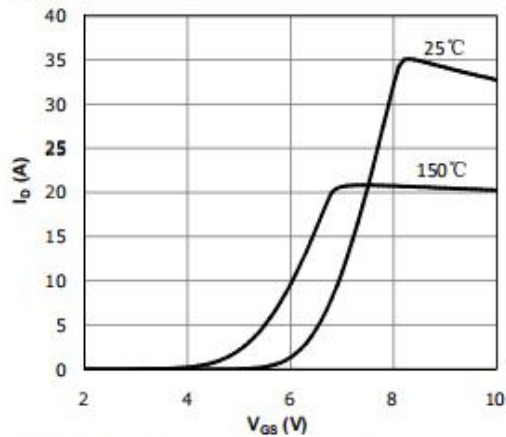


Fig 4: V_{TH} vs. T_J Temperature Characteristics

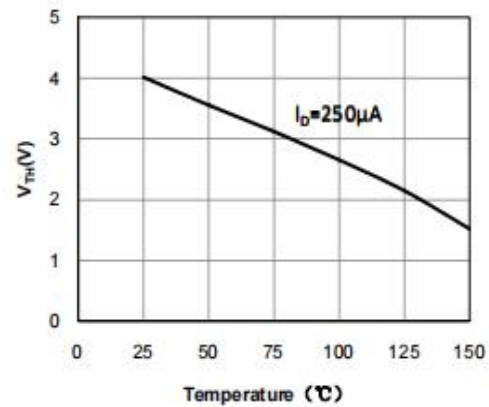


Fig 5: $R_{DS(on)}$ vs. I_{DS} Characteristics ($T_J=25^\circ\text{C}$)

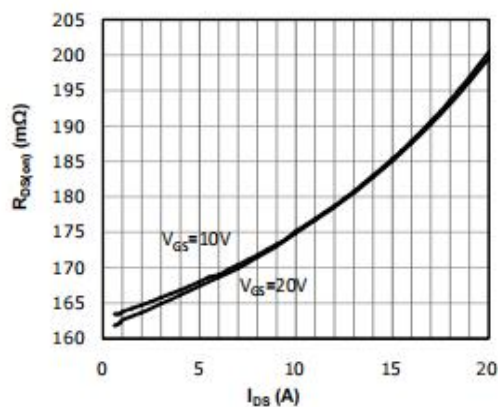


Fig 6: $R_{DS(on)}$ vs. Temperature

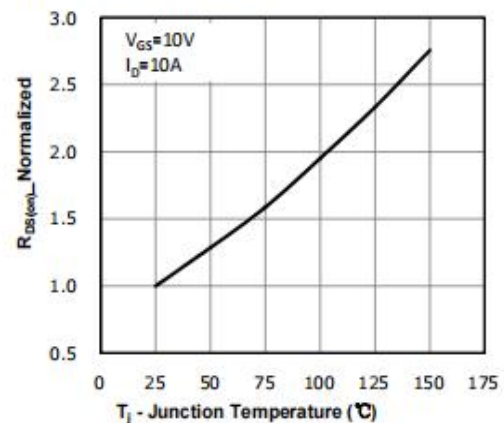


Fig 7: BV_{DS} vs. Temperature

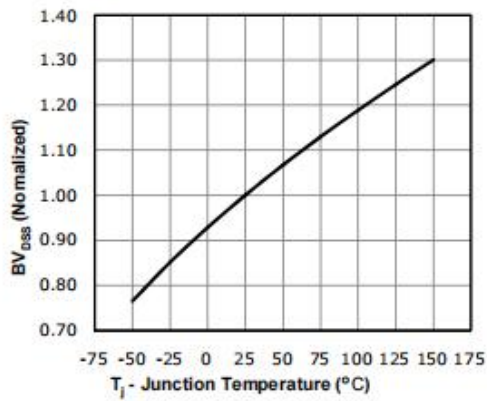


Fig 8: $R_{DS(on)}$ vs. Gate Voltage

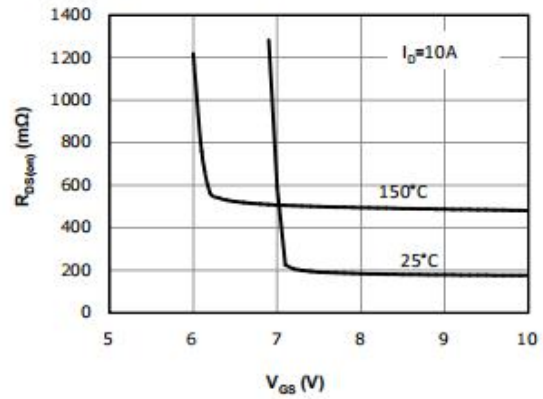


Fig 9: Body-diode Forward Characteristics

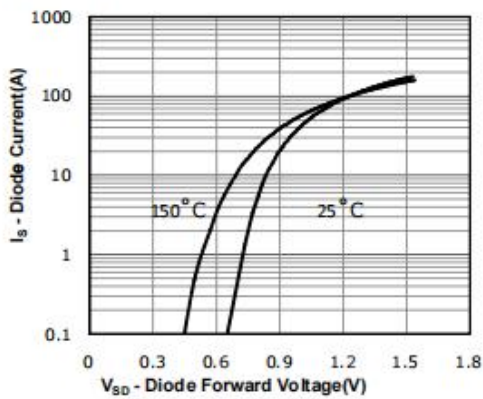


Fig 10: Gate Charge Characteristics

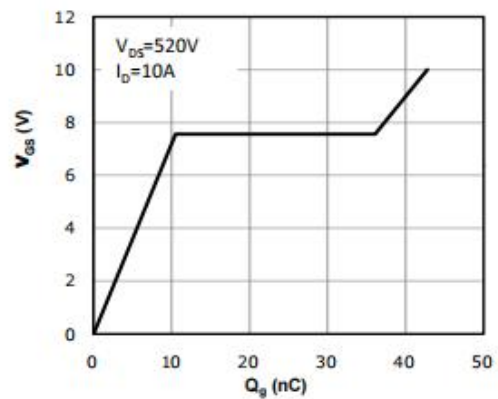


Fig 11: Capacitance Characteristics

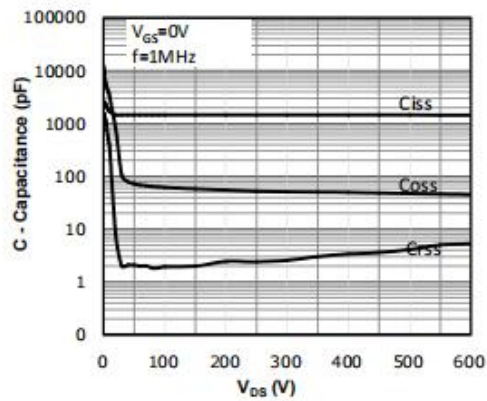


Fig 12: Safe Operating Area

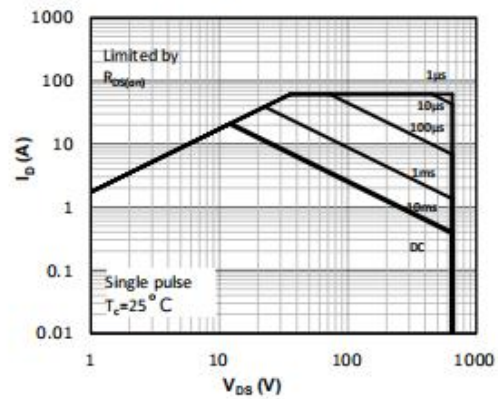
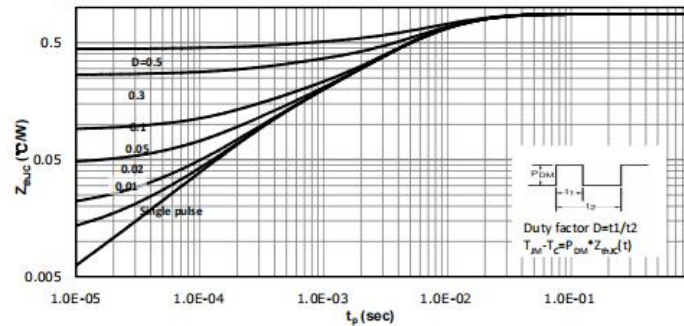
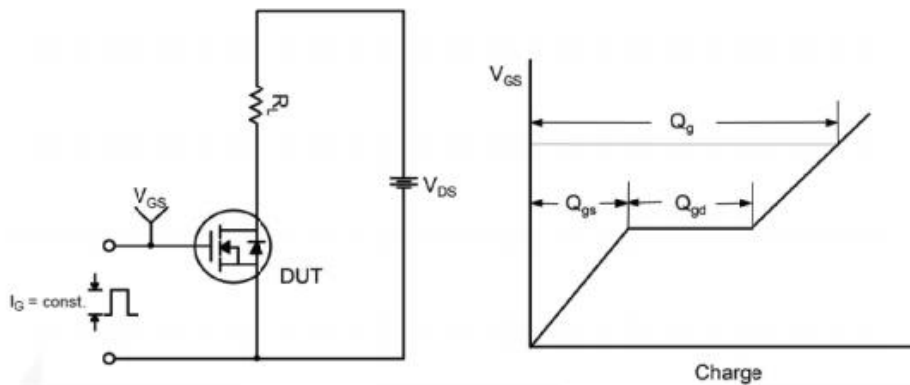


Fig 13: Max. Transient Thermal Impedance

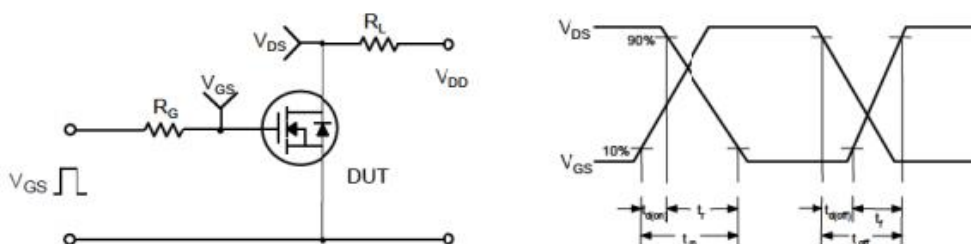


Test Circuit and Waveform

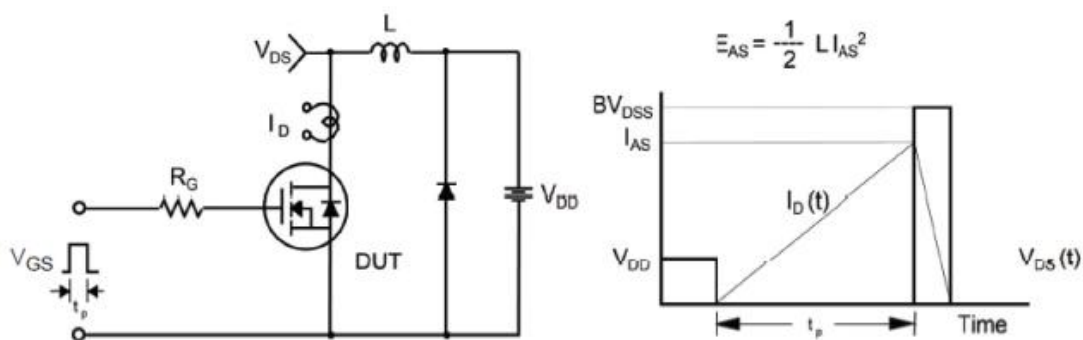
Gate Charge Test Circuit & Waveform

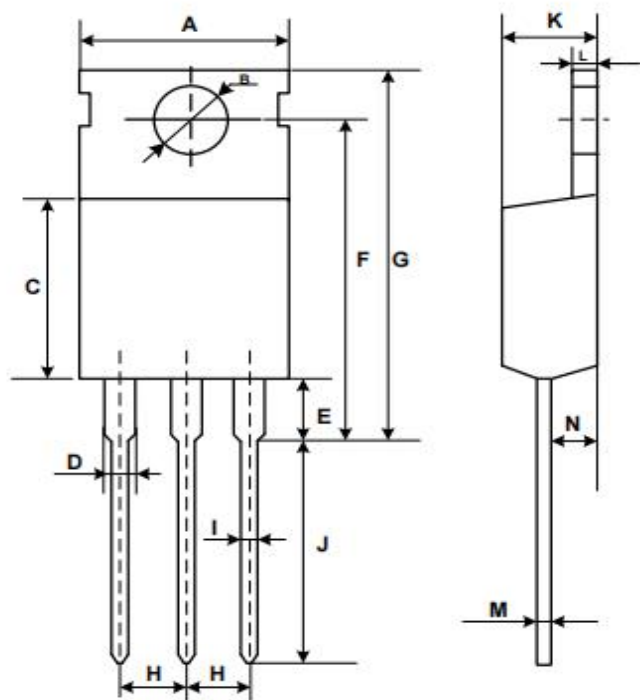


Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



Package Dimensions TO-220


SYMBOL	MM	
	MIN	MAX
A	9.70	10.30
B	3.40	3.80
C	8.80	9.40
D	1.17	1.47
E	2.60	3.50
F	15.10	16.70
G	19.55MAX	
H	2.54REF	
I	0.70	0.95
J	9.35	11.00
K	4.30	4.77
L	1.20	1.45
M	0.40	0.65
N	2.20	2.60



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